

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/709,759	LIAW ET AL.	
Examiner	Art Unit		
Dustin Nguyen	2154		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
710	38, 51	3/26/2007	DN
710	64, 73	3/26/2007	DN
709	218, 219	3/26/2007	DN